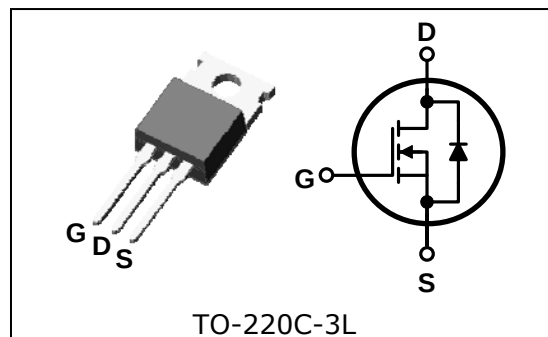


SWITCHING REGULATOR APPLICATIONS

Features

- High Voltage : $BV_{DSS}=500V(\text{Min.})$
- Low C_{rss} : $C_{rss}=21pF(\text{Typ.})$
- Low gate charge : $Q_g=43nC(\text{Typ.})$
- Low $R_{DS(on)}$: $R_{DS(on)}=0.46\Omega(\text{Max.})$

PIN Connection

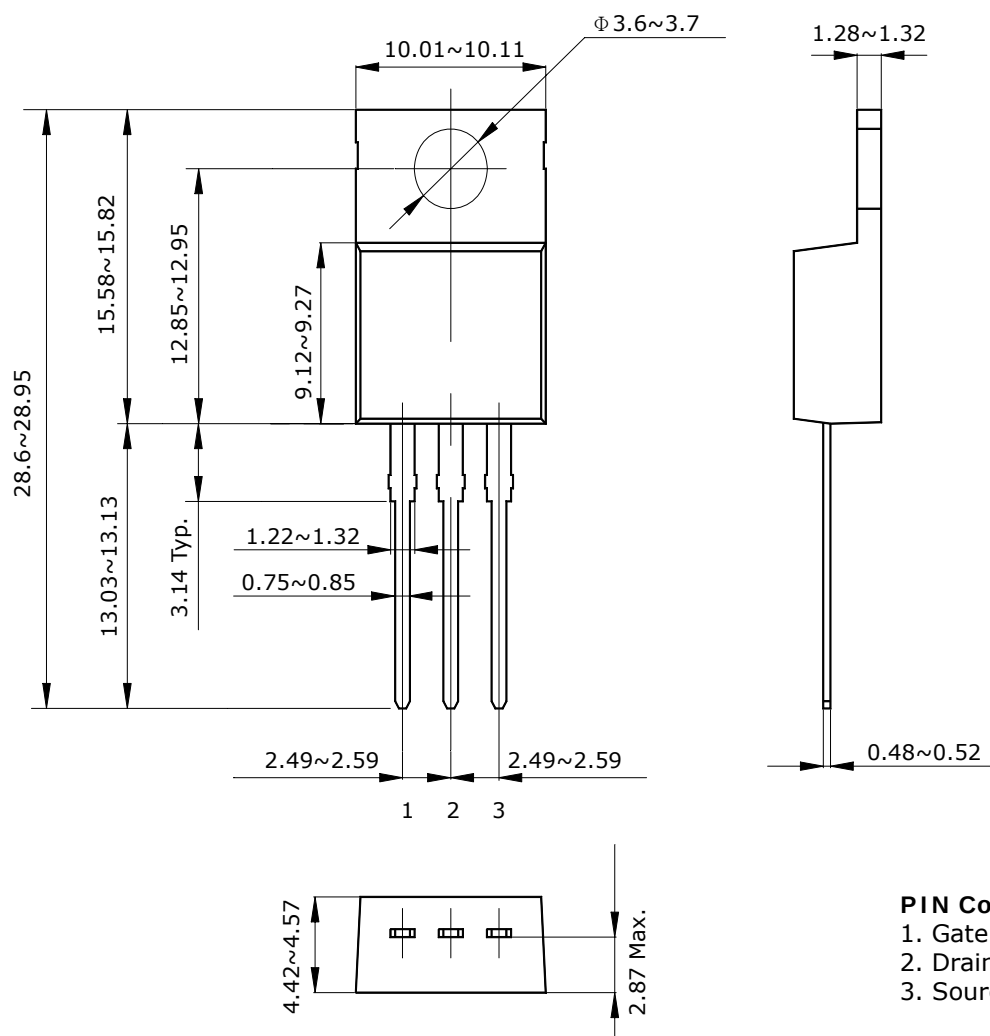


Ordering Information

Type NO.	Marking	Package Code
MP13N50	MP13N50C	TO-220C-3L

Outline Dimensions

unit : mm



Absolute Maximum Ratings

Power MOSFET

Symbol	Parameter	Value	Units
V _{DSS}	Drain Source Voltage	500	V
I _D	Continuous Drain Current(@Tc=25°C)	13*	A
	Continuous Drain Current(@Tc=100°C)	8*	A
I _{DM}	Drain Current Pulsed (Note1)	52*	A
V _{GS}	Gate to Source Voltage	±30	V
E _{AS}	Single Pulsed Avalanche Energy (Note2)	845	mJ
E _{AR}	Repetitive Avalanche Energy (Note1)	5	mJ
dv/dt	Peak Diode Recovery dv /dt (Note3)	3.5	V/ ns
P _D	Total Power Dissipation(@Tc=25°C)	190	W
	Derating Factor above 25°C	0.39	W/°C
T _J , T _{stg}	Junction and Storage Temperature	-55~150	°C
T _L	Channel Temperature	300	°C

*Drain current limited by maximum junction temperature

Thermal Characteristics

Symbol	Parameter	Value			Units
		Min	Typ	Max	
R _{QJC}	Thermal Resistance , Junction -to -Case	-	-	0.66	°C/W
R _{QCS}	Thermal Resistance , Case-to-Sink	-	0.5	-	°C/W
R _{QJA}	Thermal Resistance , Junction-to -Ambient	-	-	62.5	°C/W

Electrical Characteristics (T_C=25°C unless otherwise noted)

Characteristics		Symbol	Test Condition	Min	Type	Max	Unit
Gate leakage current		I _{GSS}	V _{GS} =±30V,V _{DS} =0V	-	-	±100	nA
Gate-source breakdown voltage		V _{(BR)GSS}	I _G =±10 μA,V _{DS} =0V	±30	-	-	V
Drain cut -off current		I _{DSS}	V _{DS} =500V,V _{GS} =0V	-	-	1	μA
			V _{DS} =400V,TC=125℃			10	μA
Drain -source breakdown voltage		V _{(BR)DSS}	I _D =250 μA,V _{GS} =0V	500	-	-	V
Breakdown voltage Temperature Coefficient		△BV _{DSS} / △T _J	I _D =250μA,Referenced to 25℃	-	0.5	-	V/℃
Gate threshold voltage		V _{GS(th)}	V _{DS} =10V,I _D =250 μA	3	-	4.5	V
Drain -source ON resistance		R _{DS(ON)}	V _{GS} =10V,I _D =6.5A	-	0.39	0.46	Ω
Forward Transconductance		g _{fs}	V _{DS} =50V,I _D =6.5A	-	15	-	S
Input capacitance		C _{iss}	V _{DS} =25V,	-	1580	2055	pF
Reverse transfer capacitance		C _{rss}	V _{GS} =0V,	-	21	26	
Output capacitance		C _{oss}	f=1MHz	-	180	235	
Switching time	Rise time	tr	V _{DD} =250V,	-	160	270	ns
	Turn-on time	ton	I _D =13A	-	100	210	
	Fall time	tf	R _G =9.1Ω	-	130	270	
	Turn-off time	toff	R _D =31Ω (Note4,5)	-	100	210	
Total gate charge(gate-source plus gate-drain)		Qg	V _{DD} =400V, V _{GS} =10V,	-	43	56	nC
Gate-source charge		Qgs	I _D =13A	-	10.9	-	
Gate-drain("miller") Charge		Qgd	(Note4,5)	-	18.5	-	

Source-Drain Diode Ratings and Characteristics (T_C=25°C unless otherwise noted)

Characteristics	Symbol	Test Condition	Min	Type	Max	Unit
Continuous drain reverse current	I _{DR}	-	-	-	13	A
Pulse drain reverse current	I _{DRP}	-	-	-	52	A
Forward voltage(diode)	V _{DSF}	I _{DR} =13A, V _{GS} =0V	-	-	1.4	V
Reverse recovery time	trr	I _{DR} =13A, V _{GS} =0V,	-	442	633	ns
Reverse recovery charge	Q _{rr}	dI _{DR} / dt =100 A / μs	-	2.16	3.24	μC

Note 1.Repeativity rating :pulse width limited by junction temperature

2.L=500uH I_{AS}=13A, V_{DD}=50V, R_G=0Ω, Starting T_J=25 °C

3.I_{SD}≤13A, di/dt≤300A/us, V_{DD}<BV_{DSS}, STARTING T_J=25 °C

4.Pulse Test:Pulse Width≤300us,Duty Cycle≤2%

5. Essentially independent of operating temperature.

Electrical Characteristic Curves

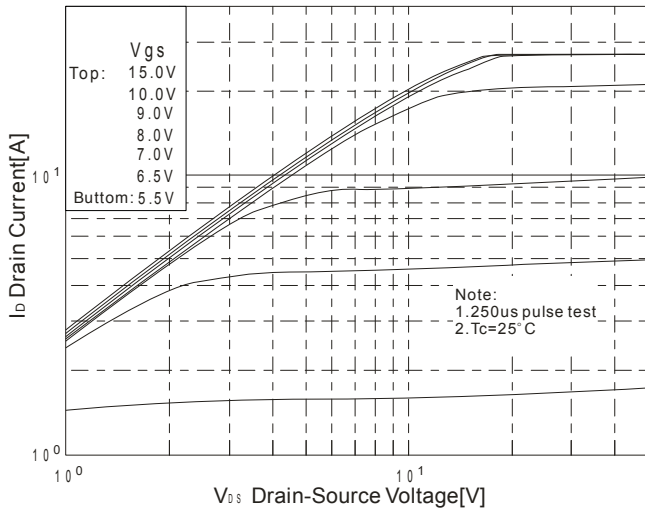


Fig.1 On Region Characteristics

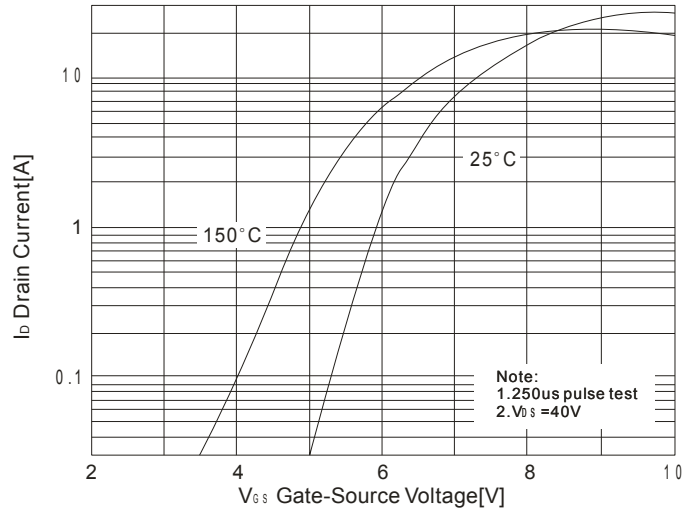


Fig.2 Transfer Characteristics

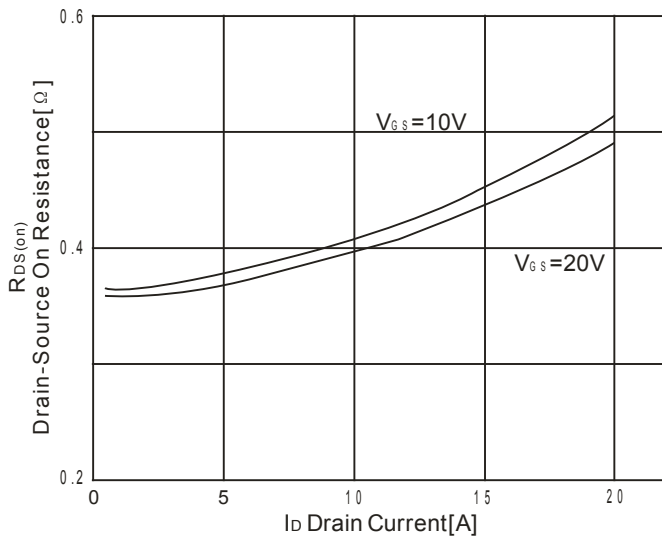


Fig.3 On-Resistance Variation vs Drain Current and Gate Voltage

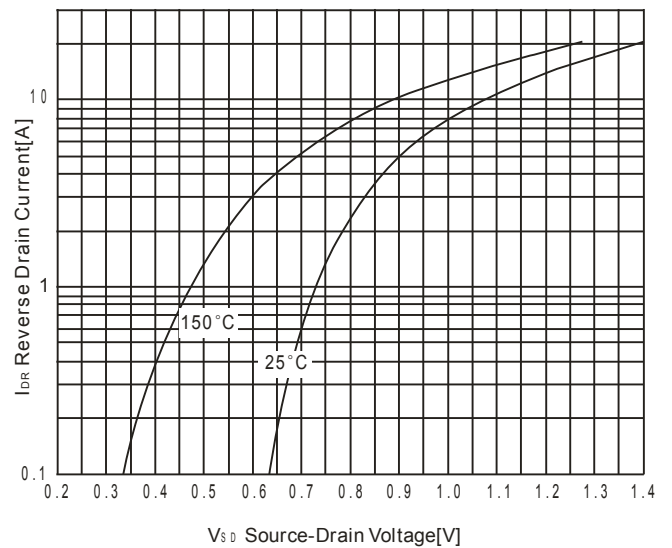


Fig.4 Body Diode Forward Voltage Variation vs. Source Current and Temperature

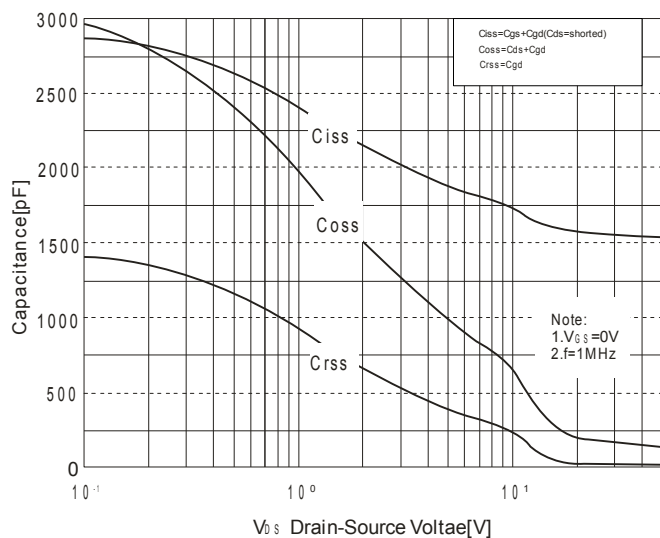


Fig.5 Capacitance Characteristics

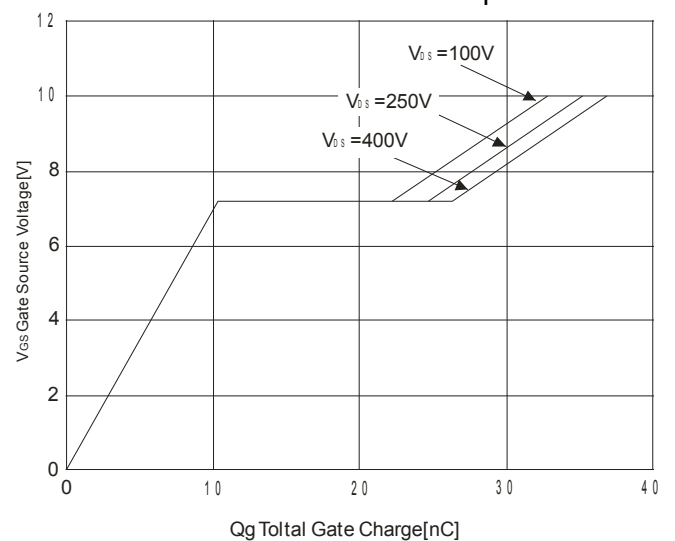


Fig.6 Gate Charge Characteristics

Electrical Characteristic Curves

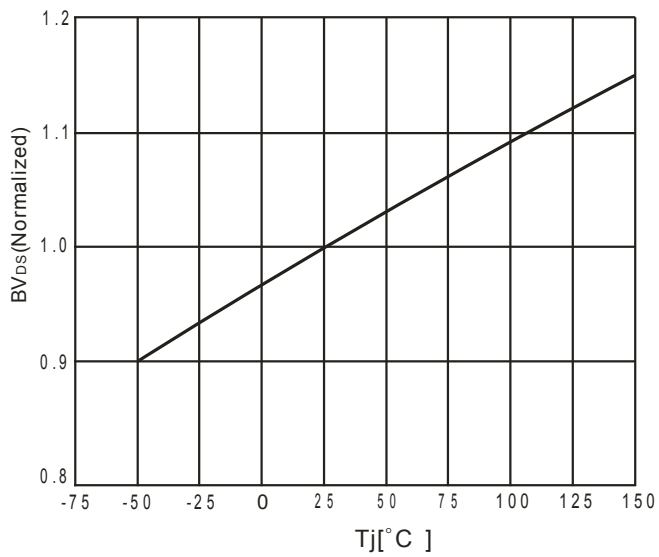


Fig.7 Breakdown Voltage Variation
vs. Temperature

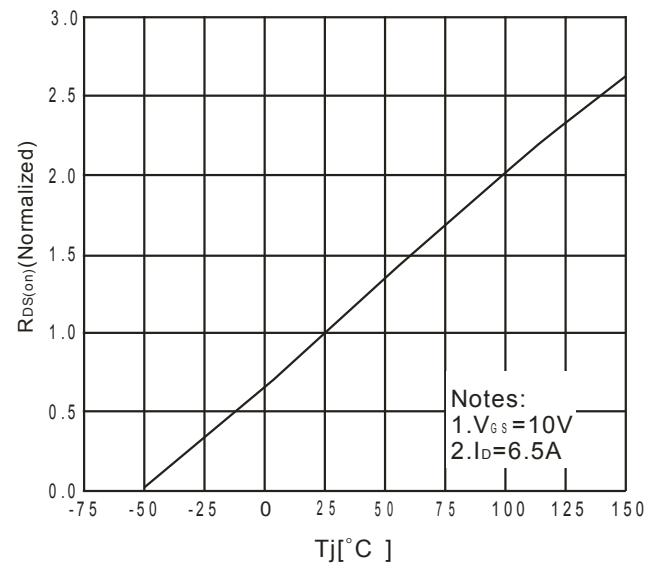
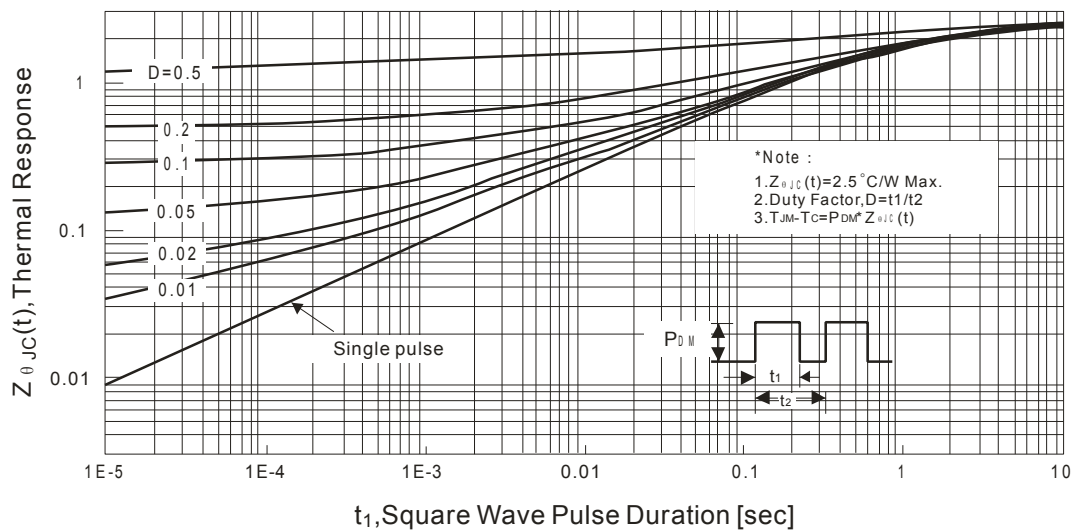


Fig.8 On-Resistance Variation
vs. Temperature



Transient thermal Response Curve

Fig. 11 Gate Charge Test Circuit & Waveform

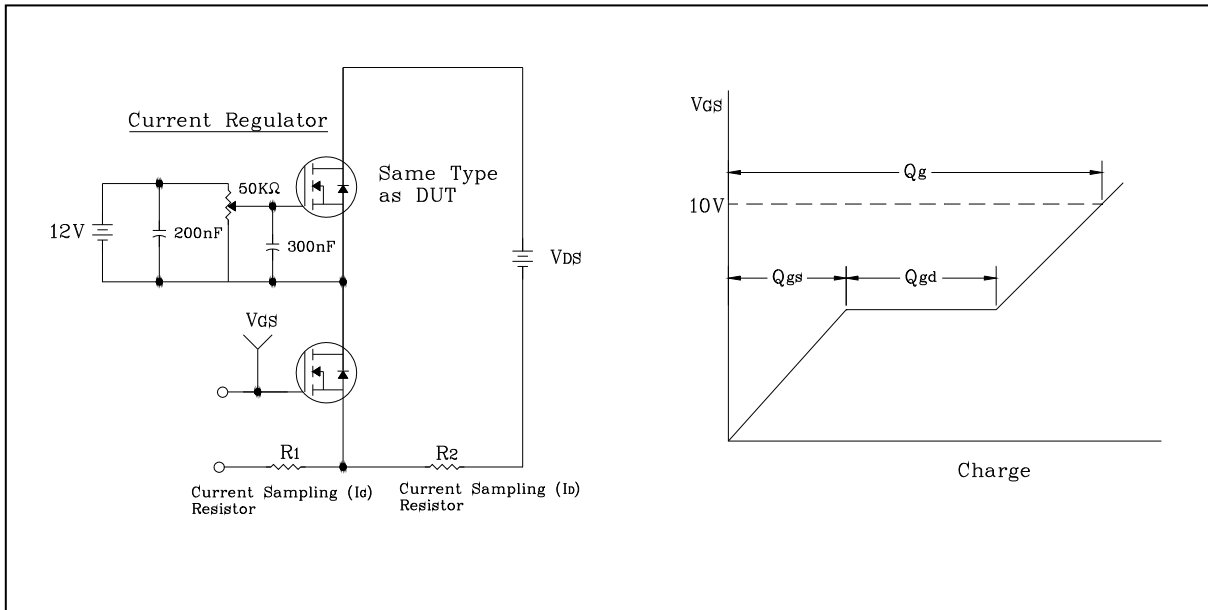


Fig. 12 Resistive Switching Test Circuit & Waveform

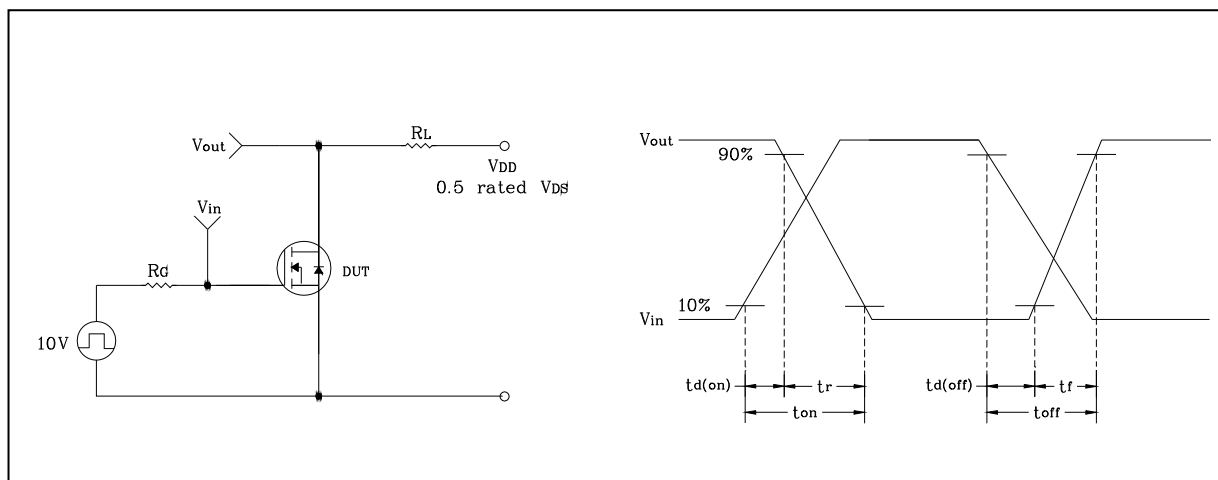


Fig. 13 E_{AS} Test Circuit & Waveform

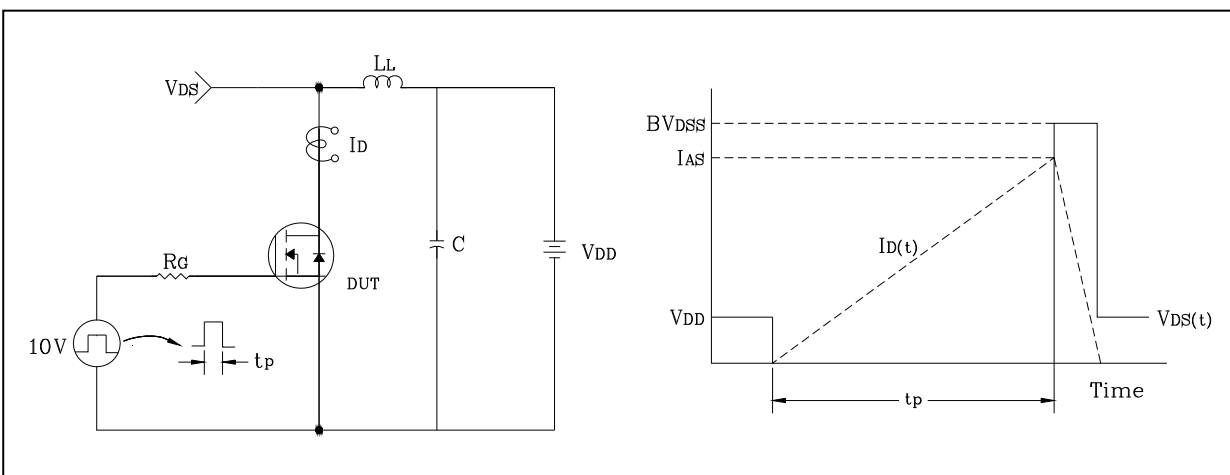


Fig. 14 Diode Reverse Recovery Time Test Circuit & Waveform

